



PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of:

Attorney Docket No.: 2267.841US03

Charles W. Extrand

Confirmation No.: 2262

Application No.: 10/662,979

Examiner: Robert W. Hodge

Filed: September 15, 2003

Group Art Unit: 1745

For: FUEL CELL WITH ULTRAPHOBIC SURFACES

INFORMATION DISCLOSURE STATEMENT

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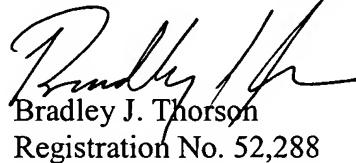
Sir:

Pursuant to 37 C.F.R. § 1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached Form PTO-1449. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed more than three months after the U.S. filing date and after the mailing date of the first Office Action on the merits, but before the mailing date of a Final Action or Notice of Allowance.

This application was filed after June 30, 2003; therefore, copies of cited U.S. patents and U.S. published applications are not included.

Respectfully submitted,



Bradley J. Thorson
Registration No. 52,288

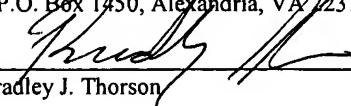
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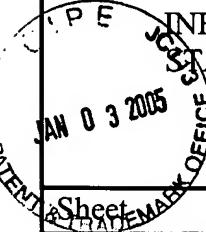
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Application Number	10/662,979
Filing Date	September 15, 2003
First Named Inventor	Charles W. Extrand
Art Unit	2262
Examiner Name	Robert W. Hodge
Attorney Docket Number	2267.841US03

Sheet

1 of 7

U.S. PATENT DOCUMENTS

EXAMINER INITIAL ¹	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number-Kind Code ² (if known)		
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		US-6,660,363 B1	12/09/2003	Wilhelm Barthlott
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		Country Code ³ Number ⁴ Kind Code ⁵ (if known)			
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		WEI JIN et al., <u>Wetting Hysteresis at the Molecular Scale</u> , <i>Physical Review Letters</i> , February 24, 1997, vol. 78, no. 8, pp. 1520-1523	
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